



# 제25회 한국반도체학술대회

The 25<sup>th</sup> Korean Conference on Semiconductors

2018년 2월 5일(월)-7일(수), 강원도 하이원리조트 컨벤션 호텔

2018년 2월 6일(화), 09:00-10:45

Room F (봉래, 6층)

## F. Silicon and Group-IV Devices and Integration Technology 분과

### [TF1-F] Neuromorphic Device and Application

TF1-F-1 09:00-09:15	<b>Behavior Analysis of Gated Schottky Diode as a Synaptic Device</b> Jong-Ho Bae, Suhwan Lim, Jai-Ho Eum, Byung-Gook Park, and Jong-Ho Lee <i>Department of Electrical and Computer Engineering and ISRC, Seoul National University</i>
TF1-F-2 09:15-09:30	<b>Steep Subthreshold Swing Characteristics of Positive Feedback Diode in FinFET Technology</b> Kyu-Bong Choi, Sung Yun Woo, and Jong-Ho Lee <i>Department of ECE and ISRC, Seoul National University</i>
TF1-F-3 09:30-09:45	<b>Study on Source/Drain Metal Contact Characteristics in a Poly-Si Reconfigurable Field Effect Transistor</b> Jai-Ho Eum, Jong-Ho Bae, and Jong-Ho Lee <i>Department of Electrical and Computer Engineering, ISRC, Seoul National University</i>
TF1-F-4 09:45-10:00	<b>Neuromorphic Behaviors of HfO<sub>2</sub> ReRAM by Pulse Frequency Modulation</b> Dong Keun Lee <sup>1</sup> , Min-Hwi Kim <sup>1</sup> , Suhyun Bang <sup>1</sup> , Tae-Hyeon Kim <sup>1</sup> , Yeon-Joon Choi <sup>1</sup> , Seongjae Cho <sup>2</sup> , and Byung-Gook Park <sup>1</sup> <i><sup>1</sup>ISRC and Department of Electrical and Computer Engineering, Seoul National University, <sup>2</sup>Department of Electronics Engineering, Gachon University</i>
TF1-F-5 10:00-10:15	<b>Implementation of Neuromorphic System with Neuron Circuit Retaining Overflow</b> Jeong-Jun Lee, Jungjin Park, Sungmin Hwang, and Byung-Gook Park <i>Department of Electrical Engineering, Seoul National University</i>
TF1-F-6 10:15-10:30	<b>Classification for Grayscale Images Using Supervised Spike Rate-Based Learning</b> Seongbin Oh, Chul-Heung Kim, SooChang Lee, Byung-Gook Park, and Jong-Ho Lee <i>Department of Electrical and Computer Engineering, ISRC, Seoul National University</i>
TF1-F-7 10:30-10:45	<b>An Analysis of Hot Carrier Injection in Asymmetric Dual Gate Structure</b> Taejin Jang, Myung-Hyun Baek, and Byung-Gook Park <i>Department of Electrical Engineering, Seoul National University</i>